

# Chem 20™

Chemical Particle Counter



Leading-edge microelectronic processes require very clean process chemicals that are highly filtered and regulated to a particle size of 20 nm or below. With 20 nm particle sensitivity, the new PMS Chem 20 Chemical Particle Counter is the world's most sensitive particle sensor for high purity process chemicals.

Extensive data on chemical distribution and packaging systems proves that the PMS Chem 20 sensor, with 20 nm sensitivity, detects larger concentrations of particles with better statistics than competitive products. The Chem 20 Chemical Particle Counter is a valuable tool that enables facility and process engineers to quickly detect and characterize chemical particle sources before they impact process and device performance.

## BENEFITS

- Detect 20 nm PSL & 9 nm Au particles in real time
- Detect yield-limiting particles (not possible with competitive technologies)
- React quickly to particle excursions long before surface scan or yield data are available
- Optimize chemical delivery systems from the loading dock to point-of-process
- Tighten process control limits through improved sample population statistics

## FEATURES

- Advanced laser optics and detectors enable detection of 20 nm polymer and 9 nm metallic particles in chemicals
- On-board chemical flow meter to set sample flow
- First particle counter optimized for low and high refractive index chemicals for improved performance:
  - Chem 20 sensor, for chemicals with lower indices of refraction
  - Chem 20-HI sensor, tailored for sulfuric acid and other higher-index chemicals
- On-board leak detection to provide alarm upon an internal chemical leak
- Low-flow detector and alarm to ensure consistent data
- Bubble detector to optimize data and protect sensor
- Two view modes optimize instrument operation for very dirty or very clean applications, extending product application space
- Local data display
- Flexible communications systems support legacy data acquisition systems

## APPLICATIONS

- Real-time particle monitoring within chemical distribution systems
- Point-of-process monitoring
- Chemical packaging operations monitoring
- Chemical filter performance and efficiency characterization
- Performance testing of chemical handling components

# Chem 20™

## Chemical Particle Counter

## Specifications

Size range	≥ 20 nm PSL and 9 nm Au minimum detection limit	
Channels	4	
Channel sizes	20, 50, 70, 100 nm	
Flow rate (ml/min)	35 ml/min	
Zero count	< 100 counts per liter	
Maximum concentration <sup>1</sup>	<b>High Resolution Mode</b> 2500 P/ml ≥ 20 nm; 1000 P/ml ≥ 100 nm	<b>High Concentration Mode</b> 500,000 P/ml > 20 nm; 10,000 P/ml > 100 nm
Sample temperature	59 – 104 °F (15 – 40 °C)	
Maximum pressure	75 psi, max	
Wetted surface materials	PFA, PTFE, Sapphire, Kel-F®, Kalrez® 4079	
Exterior surface	316L stainless steel enclosure	
External Dimensions (l, w, h)	20.0 x 16.8 x 11.1 in (50.8 x 42.7 x 28.3 cm)	
Weight	64.5 lb (29.2 kg)	
Power	100 – 240 VAC	
Laser classification	Class I complies with US21 CFR 1040.10 and EN60825-1. Internally an enclosed Class IV laser is used per EN60825-1.	
Communications	Ethernet (PMS protocol), 4-20 mA (5 outputs: 4 size channels, 1 sensor status), RS-232 (set up and diagnostics only)	
Status indicator	LCD display and one (1) tri-color LED. Indicates operation and communication status, and laser, sample flow or internal-leak status	
Calibration	Sensors calibrated using PSL particles in pure water. Materials used are traceable to National Institute of Standards & Technology (NIST) and/or Japanese Industrial Standards (JIS).	
Environment	Temperature: 64 – 82 °F (18 – 28 °C) ± 1 °C/hr Humidity: 5 - 90%, Non-Condensing Sensor must be installed in a conditioned environment with stable temperature control. Indoor use only; Pollution degree 2 Isolated from excessive machinery or vehicle vibration Over-voltage (transients) Category II Ordinary protection (not protected against harmful ingress of moisture) Class I environment (Electrical earth ground from the mains power source to the product input is required for safety purposes)	

<sup>1</sup>Less than 10% coincidence loss, measured at the maximum recommended concentration.

### HEADQUARTERS

5475 Airport Blvd  
Boulder, Colorado 80301 USA  
T: +1 303 443 7100, +1 800 238 1801

Instrument Service & Support  
T: +1 800 557 6363  
Customer Response Center  
T: +1 877 475 3317  
E: info@pmeasuring.com

### GLOBAL OFFICES

BRAZIL  
T: +55 11 5188 8227  
E: pmsbrazil@pmeasuring.com

CHINA  
T: +86 21 6113 3600  
E: pmschina@pmeasuring.com

FRANCE  
T: +33 (0)6 82 99 17 98  
E: pmsfrance@pmeasuring.com

GERMANY  
T: +49 6151 6671 632  
E: pmsgermany@pmeasuring.com

ITALY  
T: +39 06 9053 0130  
E: pmsrli@pmeasuring.com

JAPAN  
T: +81 3 5298 8175  
E: pmsjapan@pmeasuring.com

KOREA  
T: +82 31 286 5790  
E: pmskorea@pmeasuring.com

MEXICO  
T: +52 55 2271 5106  
E: pmsmexico@pmeasuring.com

NORDIC  
T: +45 707 028 55  
E: pmsnordic@pmeasuring.com

PUERTO RICO  
T: +1 787 718 9096  
E: pmspuertorico@pmeasuring.com

SINGAPORE  
T: +65 6496 0330  
E: pmsingapore@pmeasuring.com

SWITZERLAND  
T: +41 71 987 01 01  
E: info@cas.ch

TAIWAN  
T: 886-3-5525300 Ext: 301  
E: pmstaiwan@pmeasuring.com

UNITED KINGDOM  
T: +44 1684 581 000  
E: pmsemea@pmeasuring.com

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